

**REVISIONS**

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Add case outline 2 for device types 01 and 02. Update format. Editorial changes throughout.	89-11-07	M. A. Frye
B	Changes to large-signal voltage gain test and to the output voltage swing test. Changes IAW NOR 5962-R193-93.	93-08-26	M. A. Frye
C	Add case outline K. Change boilerplate to add one-part part numbers. Add delta test limits. Redrawn.	96-11-25	R. Monnin
D	Add radiation hardness requirements. Update boilerplate. -rrp	98-06-19	R. Monnin
E	Change to the slew rate test condition $A_{VCL}$ in table I. -rrp	00-10-04	R. Monnin
F	Add case outline D. Remove radiation exposure circuit. Changes made to 1.2.4, 1.3, 3.2.3, figure 1, and table IIA. Update boilerplate to reflect current requirements. -rrp	03-03-19	R. Monnin

THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

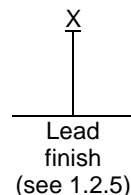
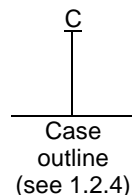
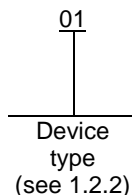
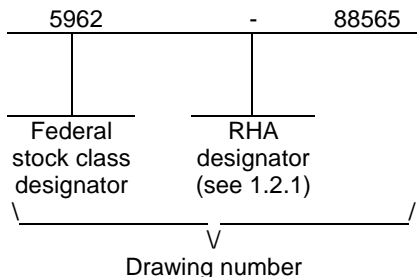
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REV STATUS	REV	F	F	F	F	F	F	F	F	F	F	F	F	F						
OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10	11								
PMIC N/A	PREPARED BY Gary Zahn	<b>DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216 <a href="http://www.dsc.dla.mil">http://www.dsc.dla.mil</a></b>																		
<b>STANDARD MICROCIRCUIT DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS  AND AGENCIES OF THE DEPARTMENT OF DEFENSE  AMSC N/A	CHECKED BY Ray Monnin																			
	APPROVED BY Michael A Frye	<b>MICROCIRCUIT, LINEAR, RADIATION HARDENED, LOW NOISE, QUAD OPERATIONAL AMPLIFIERS, MONOLITHIC SILICON</b>																		
	DRAWING APPROVAL DATE 88-08-18																			
	REVISION LEVEL F	SIZE A	CAGE CODE <b>67268</b>	<b>5962-88565</b>																
		SHEET		1 OF 11																

1. SCOPE

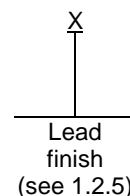
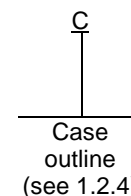
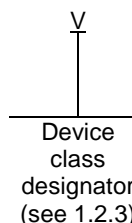
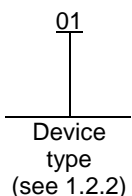
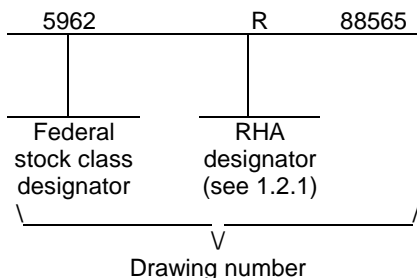
1.1 Scope. This drawing documents two product assurance class levels consisting of high reliability (device classes Q and M) and space application (device class V). A choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of Radiation Hardness Assurance (RHA) levels are reflected in the PIN.

1.2 PIN. The PIN is as shown in the following examples.

For device classes M and Q:



For device class V:



1.2.1 RHA designator. Device classes Q and V RHA marked devices meet the MIL-PRF-38535 specified RHA levels and are marked with the appropriate RHA designator. Device class M RHA marked devices meet the MIL-PRF-38535, appendix A specified RHA levels and are marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	OP-470A	Very low noise, quad, operational amplifier
02	OP-471A	High speed, low noise, quad, operational amplifier

1.2.3 Device class designator. The device class designator is a single letter identifying the product assurance level as listed below. Since the device class designator has been added after the original issuance of this drawing, device classes M and Q designators will not be included in the PIN and will not be marked on the device.

<u>Device class</u>	<u>Device requirements documentation</u>
M	Vendor self-certification to the requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A
Q or V	Certification and qualification to MIL-PRF-38535

<b>STANDARD MICROCIRCUIT DRAWING</b> DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE <b>A</b>		<b>5962-88565</b>
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1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
C	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
D	GDFP1-F14 or CDFP2-F14	14	Flat pack
2	CQCC1-N20	20	Square leadless chip carrier
3	CQCC1-N28	28	Square leadless chip carrier
K	GDFP2-F24 or CDFP3-F24	24	Flat pack

1.2.5 Lead finish. The lead finish is as specified in MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

1.3 Absolute maximum ratings. 1/

Supply voltage ( $V_{CC}$ ) .....	$\pm 18$ V dc
Differential input voltage .....	$\pm 1$ V dc <u>2/</u>
Differential input current .....	$\pm 25$ mA <u>2/</u>
Input voltage .....	Supply voltage
Output short circuit duration .....	Continuous
Storage temperature range .....	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Lead temperature (soldering, 60 seconds) .....	$+300^{\circ}\text{C}$
Power dissipation ( $P_D$ ):	
Cases C and 2 .....	800 mW
Case D .....	550 mW
Case 3 .....	500 mW
Case K .....	440 mW
Maximum junction temperature ( $T_J$ ) .....	$+150^{\circ}\text{C}$
Thermal resistance, junction-to-case ( $\theta_{JC}$ ) .....	See MIL-STD-1835
Thermal resistance, junction-to-ambient ( $\theta_{JA}$ ):	
Cases C and 2 .....	$100^{\circ}\text{C/W}$
Case D .....	$140^{\circ}\text{C/W}$
Case 3 .....	$110^{\circ}\text{C/W}$
Case K .....	$69^{\circ}\text{C/W}$

1.4 Recommended operating conditions.

Ambient operating temperature range ( $T_A$ ) .....	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
Supply voltage ( $V_{CC}$ ) .....	$\pm 15$ V

1.5 Radiation features.

Maximum total dose available (dose rate = 50 – 300 rads(Si)/s)..... 100 Krads(Si) 3/

## 2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

- 1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
- 2/ The inputs are protected by back-to-back diodes. Current limiting resistors are not used in order to achieve low noise performance. If the differential input voltage exceeds  $\pm 1$  V, the input current should be limited to  $\pm 25$  mA.
- 3/ These parts may be dose rate sensitive in a space environment and may demonstrate enhanced low dose rate effects. Radiation end point limits for the noted parameters are guaranteed only for the conditions specified in MIL-STD-883, method 1019, condition A.

<b>STANDARD</b> <b>MICROCIRCUIT DRAWING</b> DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE <b>A</b>		<b>5962-88565</b>
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SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Method Standard Microcircuits.
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Radiation exposure circuit. The radiation exposure circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing and acquiring activity upon request.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

3.5.1 Certification/compliance mark. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A.

Table with 4 columns: Standard Description, Size, Revision Level, and Sheet Number. Row 1: STANDARD MICROCIRCUIT DRAWING, SIZE A, 5962-88565. Row 2: DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000, REVISION LEVEL F, SHEET 4.

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T <sub>A</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit	
					Min	Max		
Input offset voltage	V <sub>IO</sub>		1	01		±0.4	mV	
			2, 3			±0.6		
			M,D,P,L,R		1			±0.6
				02	1			±0.8
			2, 3			±1.2		
			M,D,P,L,R		1			±1.0
Input offset current	I <sub>IO</sub>	V <sub>CM</sub> = 0 V	1	All		±10	nA	
			2, 3			±20		
			M,D,P,L,R		1			50
Input bias current	I <sub>IB</sub>	V <sub>CM</sub> = 0 V	1	All		±25	nA	
			2, 3			±50		
			M,D,P,L,R		1			±500
Input noise voltage	E <sub>n</sub>	f <sub>o</sub> = 1 Hz to 100 Hz T <sub>A</sub> = +25°C <u>3/</u>	7	01		110	nV RMS	
				02		265		
Large-signal voltage gain	A <sub>VS</sub>	V <sub>O</sub> = ±10 V, R <sub>L</sub> = 10 kΩ	4	01	1000		V/mV	
			5, 6		750			
			M,D,P,L,R		4	100		
					4	500		
		V <sub>O</sub> = ±10 V, R <sub>L</sub> = 2 kΩ <u>3/</u>	5, 6	400				
			4	02	500			
		5, 6	375					
		M,D,P,L,R	4		50			

See footnotes at end of table.

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TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T <sub>A</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Large-signal voltage gain	A <sub>VS</sub>	V <sub>O</sub> = ±10 V, R <sub>L</sub> = 2 kΩ <u>3/</u>	4	02	350		V/mV
			5, 6		250		
Output voltage swing	V <sub>OP</sub>	R <sub>L</sub> = 2 kΩ <u>3/</u>	4, 5, 6	All	±12		V
Supply current <u>4/</u>	I <sub>S</sub>	No load  M,D,P,L,R	1, 2, 3	All		11	mA
			1			11	
Slew rate	SR	A <sub>VCL</sub> = +21, R <sub>L</sub> = 10 kΩ, T <sub>A</sub> = +25°C <u>3/</u>	7	01	1.4		V/μs
				02	6.5		
Common-mode rejection	CMR	V <sub>CM</sub> = IVR = ±11 V <u>3/ 5/</u>	1	01	110		dB
			2, 3		100		
			1	02	105		
			2, 3		100		
Power supply rejection ratio	PSRR	V <sub>CC</sub> = ±4.5 V to ±18 V <u>3/</u>	1	01		1.8	μV/V
			2, 3			5.6	
			1	02		5.6	
			2, 3			10	

- 1/ Devices supplied to this drawing have been characterized through all levels M, D, P, L, R of irradiation. However, this device is only tested at the "R" level. Pre and Post irradiation values are identical unless otherwise specified in table I. When performing post irradiation electrical measurements for any RHA level, T<sub>A</sub> = +25°C. V<sub>CC</sub> = ±15 V, R<sub>S</sub> = 50 Ω.
- 2/ These parts may be dose rate sensitive in a space environment and may demonstrate enhanced low dose rate effects. Radiation end point limits for the noted parameters are guaranteed only for the conditions specified in MIL-STD-883, method 1019, condition A.
- 3/ This parameter is not tested post-irradiation.
- 4/ I<sub>S</sub> limit equals the total of all amplifiers.
- 5/ IVR is defined as the V<sub>CM</sub> range used for the CMR test.

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Device types	01 and 02			
Case outlines	C and D	2	3	K
Terminal number	Terminal symbol			
1	OUT A	NC	NC	OUT A
2	-IN A	OUT A	OUT A	-IN A
3	+IN A	-IN A	-IN A	NC
4	+V <sub>CC</sub>	+IN A	NC	NC
5	+IN B	NC	NC	+IN A
6	-IN B	+V <sub>CC</sub>	+IN A	+V <sub>CC</sub>
7	OUT B	NC	NC	+IN B
8	OUT C	+IN B	+V <sub>CC</sub>	NC
9	-IN C	-IN B	NC	NC
10	+IN C	OUT B	+IN B	NC
11	-V <sub>CC</sub>	NC	NC	-IN B
12	+IN D	OUT C	NC	OUT B
13	-IN D	-IN C	-IN B	OUT C
14	OUT D	+IN C	OUT B	-IN C
15	----	NC	NC	NC
16	----	-V <sub>CC</sub>	OUT C	NC
17	----	NC	-IN C	NC
18	----	+IN D	NC	+IN C
19	----	-IN D	NC	-V <sub>CC</sub>
20	----	OUT D	+IN C	+IN D
21	----	----	NC	NC
22	----	----	-V <sub>CC</sub>	NC
23	----	----	NC	-IN D
24	----	----	+IN D	OUT D
25	----	----	NC	----
26	----	----	NC	----
27	----	----	-IN D	----
28	----	----	OUT D	----

FIGURE 1. Terminal connections.

<b>STANDARD MICROCIRCUIT DRAWING</b> DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE <b>A</b>		<b>5962-88565</b>
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3.6 Certificate of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DSCC-VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change as defined in MIL-PRF-38535, appendix A.

3.9 Verification and review for device class M. For device class M, DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 49 (see MIL-PRF-38535, appendix A).

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

##### 4.2.1 Additional criteria for device class M.

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015.
  - (2)  $T_A = +125^{\circ}\text{C}$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.

##### 4.2.2 Additional criteria for device classes Q and V.

- a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.
- c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

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TABLE IIA. Electrical test requirements.

Test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)	Subgroups (in accordance with MIL-PRF-38535, table III)	
	Device class M	Device class Q	Device class V
Interim electrical parameters (see 4.2)	1	1	1
Final electrical parameters (see 4.2)	1,2,3,4,5,6 <u>1/</u>	1,2,3,4,5,6 <u>1/</u>	1,2,3,4, <u>1/ 2/</u> 5,6
Group A test requirements (see 4.4)	1,2,3,4,5,6,7	1,2,3,4,5,6,7	1,2,3,4,5,6,7
Group C end-point electrical parameters (see 4.4)	1	1	1 <u>2/</u>
Group D end-point electrical parameters (see 4.4)	1	1	1
Group E end-point electrical parameters (see 4.4)	----	----	1, 4

1/ PDA applies to subgroup 1.

2/ See table IIB for delta measurement parameters.

Table IIB. 240 hour burn-in and group C end-point electrical parameters.

Parameter	Device type	Limit		Delta	
		Min	Max	Min	Max
V <sub>OS</sub>	01		0.4 mV		100 μV
	02		0.8 mV		250 μV
I <sub>OS</sub>	01		10 nA		5 nA
	02		10 nA		5 nA
I <sub>B</sub>	01		±25 nA		5 nA
	02		±25 nA		5 nA

4.4 Conformance inspection. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections and as specified. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection.

- a. Tests shall be as specified in table IIA herein.
- b. Subgroups 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

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4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
- b.  $T_A = +125^{\circ}\text{C}$ , minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes M, Q, and V shall be as specified in MIL-PRF-38535. End-point electrical parameters shall be as specified in table IIA herein.

4.4.4.1 Total dose irradiation testing. Total dose irradiation testing shall be performed in accordance with MIL-STD-883 method 1019 condition A and as specified herein.

4.4.4.1.1 Accelerated aging test. Accelerated aging tests shall be performed on all devices requiring a RHA level greater than 5k rads(Si). The post-anneal end-point electrical parameter limits shall be as specified in table I herein and shall be the pre-irradiation end-point electrical parameter limit at  $25^{\circ}\text{C} \pm 5^{\circ}\text{C}$ . Testing shall be performed at initial qualification and after any design or process changes which may affect the RHA response of the device.

4.4.4.2 Dose rate burnout. When required by the customer test shall be performed on devices, SEC, or approved test structures at technology qualifications and after any design or process changes which may effect the RHA capability of the process. Dose rate burnout shall be performed in accordance with test method 1023 of MIL-STD-883 and as specified herein.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

## 6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.3 Record of users. Military and industrial users should inform Defense Supply Center Columbus when a system application requires configuration control and which SMD's are applicable to that system. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0525.

6.4 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0547.

<b>STANDARD MICROCIRCUIT DRAWING</b> DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE <b>A</b>		<b>5962-88565</b>
		REVISION LEVEL <b>F</b>	SHEET <b>10</b>

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

6.6 Sources of supply.

6.6.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DSCC-VA and have agreed to this drawing.

6.6.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

<b>STANDARD MICROCIRCUIT DRAWING</b> DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE <b>A</b>		<b>5962-88565</b>
		REVISION LEVEL F	SHEET <b>11</b>

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 03-03-19

Approved sources of supply for SMD 5962-88565 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8856501CA	24355	OP-470AY/883C
5962-88565012A	24355	OP-470ARC/883C
5962-88565013A	<u>3/</u>	OP-470ATC/883C
5962-8856502CA	24355	OP-471AY/883C
5962-88565022A	24355	OP-471ARC/883C
5962-88565023A	24355	OP-471ATC/883C
5962-8856501VCA	24355	OP470AY/QMLV
5962-8856501V2A	24355	OP470ARC/QMLV
5962-8856501VKA	24355	OP470AN/QMLV
5962-8856502VCA	24355	OP471AY/QMLV
5962-8856502VDA	24355	OP471AM/QMLV
5962-8856502V2A	24355	OP471ARC/QMLV
5962-8856502VKA	24355	OP471AN/QMLV

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING BULLETIN – Continued.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962R8856501VCA	24355	OP470AY/QMLR
5962R8856501V2A	24355	OP470ARC/QMLR
5962R8856501VKA	24355	OP470AN/QMLR
5962R8856502VCA	24355	OP471AY/QMLR
5962R8856502VDA	24355	OP471AM/QMLR
5962R8856502V2A	24355	OP471ARC/QMLR
5962R8856502VKA	24355	OP471AN/QMLR

1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.

2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

3/ Not available from an approved source of supply.

Vendor CAGE number

24355

Vendor name and address

Analog Devices  
 RT 1 Industrial Park  
 PO Box 9106  
 Norwood, MA 02062  
 Point of contact: 1500 Space Park Drive  
 PO Box 58020  
 Santa Clara, CA 95052-8020

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.